

<b>O P E INFORMATION DISCLOSURE CITATION</b> <small>(use several sheets if necessary)</small>				Docket Number (Optional) <b>00280659AA</b>	Application Number <b>09/739,637</b>	
				Applicant(s) <b>Heching et al.</b>		
				Filing Date <b>12-20-00</b>	Group Art Unit <b>2162 3623</b>	
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS
	1	6,574,585	6-3-03	Caruso et al.		2-26-01
<b>FOREIGN PATENT DOCUMENTS</b>						
REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation
						YES
<b>RECEIVED</b> <small>SEP 17 2003</small> <b>GROUP 3600</b>						
<b>OTHER DOCUMENTS</b> ( <i>Including Author, Title, Date, Pertinent Pages, Etc.</i> )						
		1. Article from the Journal of the American Statistical Association, titled: "Fine-Tuning Some Resistant Rules for Outlier Labeling" December 1987 Vol. 82 No. 400. David C. Hoaglin and Boris Iglewicz 2. "Ratios Involving Extreme Values" done with Office of Naval Research, by W.J. Dixon pp. 68-78				
		3. Article from Technometrics Vol. 25, No. 2 dated May 1983 titled "Percentage Points for Generalized ESD Many-Outlier Procedure by Bernard Rosner at Harvard Medical School 4. Documents (Outliers In Statistical Data) by Barnett and Lewis pp. 226-230 and pg. 498 5. Documents (Box-and-Whiskers Plot) pp. 59-60				
EXAMINER			DATE CONSIDERED <i>Ronan Deanty</i> 12-7-2004			

**EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.